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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(Case No. 219.003-US)

In the Application of: **Yamada**

Serial No: **09/865,528**

Filed: **May 29, 2001**

Title: **Semiconductor Device Test Method and
Semiconductor Device Tester**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

) Group Art Unit: **2829**
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) Before Examiner: **V. Nguyen**
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22313-1450 on June 15, 2004

Date

Michiko Sites
(person signing this certificate)

Michiko Sites
Signature

SUBMISSION OF ENGLISH TRANSLATIONS

Dear Sir:

Attached hereto is an English translation of each of the following Japanese patent
applications: JP H9-61142 and JP H8-5528, which were submitted in an Information
Disclosure Statement dated March 17, 2004.

Respectfully submitted,

Date: June 15, 2004

Neil A. Steinberg
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650-968-8079